



INDIAN INSTITUTE OF TECHNOLOGY BOMBAY  
MATERIALS MANAGEMENT DIVISION  
Powai, Mumbai 400076.

PR No. 1000052510

Rfx No. 6100002707

Item Description: Add on components for Dual Beam

Sr. No.	Item Description	Detailed Technical Specification	Technical Compliance (Yes / No)	Additional Information (if any)
1.	<b>Suppressor -</b> Sw,P/N.FEI – 403527235991  ( Qty – 2 Nos )	<b>Focused Ion Dual Beam – Scanning electron Microscope (FIB-SEM)</b> which is homed in the SAIF/CSIF department is extensively used for both educational and research purposes in different departments in IIT Bombay.		
2	<b>Extractor –</b> Assy, Thawkht P/N. FEI – 1301275  ( Qty – 2 Nos )	Add-on Components : Suppressor and Extractor are add on components used in the Ion Source of the FIB-SEM. The extractor is used to extract ions from the gallium ion source. The suppressor is used to suppress the wide spread of Ions and route it towards the sample.		
3	Warranty	6 Months		